Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/055,197	LIFSHITZ ET AL.	
Examiner	Art Unit	
Jason M. Perilla	2611	

	SEAR	CHED	
Class	Subclass	Date	Examiner
375	222	12/18/2006	Je
	219	12/18/2006	,JP
	295	12/18/2006	JP
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TNI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH (INCLUDING SEAI)
	DATE	EXMR
East USPAT/USPGPUB EPO/JPO	12/18/2006	JP
Inventor Name Search EAST/EDAN	12/18/2006	JP